

**Search Notes**

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Jinhee J. Lee

Applicant(s)/Patent under  
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KLIER, JAN

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
715	text	11/26/2006	LEE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	as above	11/26/2006	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search attached	11/26/2006	LEE